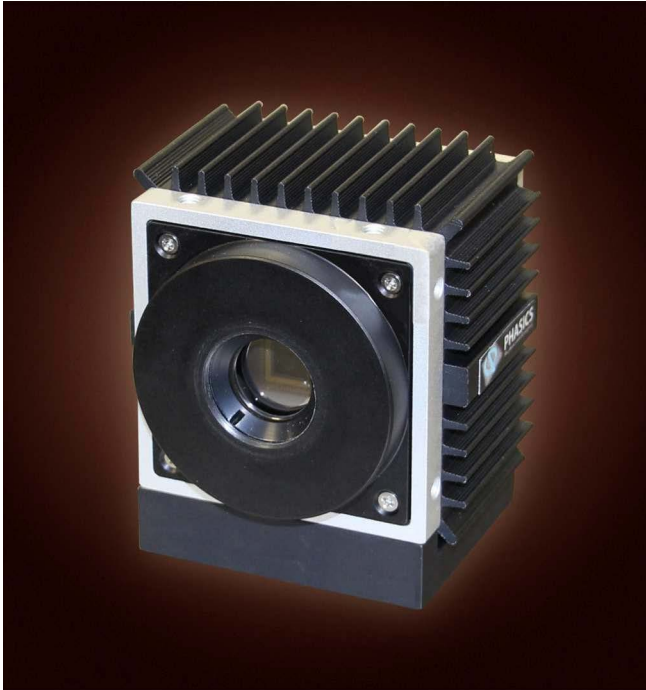




# SID4 UV WAVE FRONT SENSOR



→ The **SID4-UV** wavefront sensor benefits from PHASICS patented technology\*. It not only offers an unequalled high resolution (250x250 measurement points) but it is also compact and very easy-to-use. Thus it delivers **fast and accurate** measurement

It is a cost-effective solution for **testing quality of UV optics** such as lens used in semiconductor systems (MTF, aberrations...). It also allows full **surface inspection** of lens, mirror, wafer...

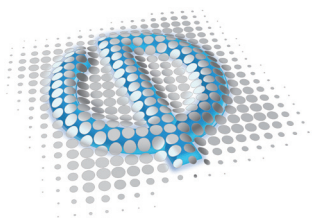
The SID4-UV is an efficient instrument for ultraviolet **laser beam measurement** (Zernike coefficients, PSF, M<sup>2</sup>, Strehl Ratio, beam profile...)

## ↓ SPECIFICATIONS

Aperture dimension	7.4 x 7.4 mm <sup>2</sup>
Spatial resolution	29.6 μm
Sampling	250 x 250
Wavelength range	250 - 400 nm
Accuracy (absolute)	10 nm RMS
Resolution (Phase)	2 nm RMS
Dynamic	> 200 μm PtV
Analysis rate	2 fps
Acquisition rate	30 fps
Computer connection	Ethernet
Dimensions (WxHxL)	45 x 30 x 100 mm
Weight	250 g

## ↘ KEY FEATURES

- Very high resolution: 250x250 phase pixels
- Large analysis pupil: 7.4 x 7.4 mm<sup>2</sup>
- Broadband
- Compact
- Cost-effective



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